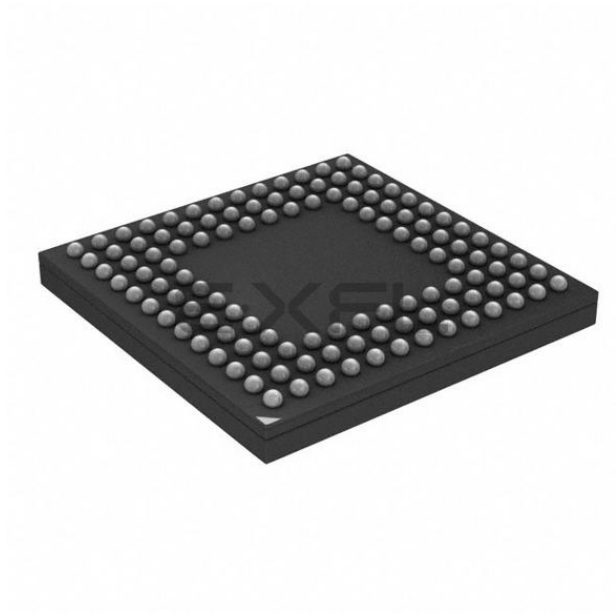
Silicon Labs - EFM32GG11B510F2048GL120-AR Datasheet



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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Obsolete
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	72MHz
Connectivity	CANbus, EBI/EMI, I²C, IrDA, LINbus, SmartCard, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, DMA, LCD, POR, PWM, WDT
Number of I/O	95
Program Memory Size	2MB (2M x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	384K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.8V
Data Converters	A/D 16x12b SAR; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	120-VFBGA
Supplier Device Package	120-BGA (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/efm32gg11b510f2048gl120-ar

3.6.6 Quad-SPI Flash Controller (QSPI)

The QSPI provides access to to a wide range of flash devices with wide I/O busses. The I/O and clocking configuration is flexible and supports many types of devices. Up to 8-bit wide interfaces are supported. The QSPI handles opcodes, status flag polling, and timing configuration automatically.

The external flash memory is mapped directly to internal memory to allow random access to any word in the flash and direct code execution. An integrated instruction cache minimizes latency and allows efficient code execution. Execute in Place (XIP) is supported for devices with this feature.

Large data chunks can be transferred with DMA as efficiently as possible with high throughput and minimimal bus load, utilizing an integrated 1 kB SRAM FIFO.

3.6.7 SDIO Host Controller (SDIO)

The SDIO is an SD3.01 / SDIO3.0 / eMMC4.51-compliant Host Controller interface for transferring data to and from SD/MMC/SDIO devices. The module conforms to the SD Host Controller Standard Specification Version 3.00. The Host Controller handles SDIO/SD/MMC Protocol at the transmission level, packing data, adding cyclic redundancy check (CRC), Start/End bits, and checking for transaction format correctness.

3.6.8 Universal Serial Bus (USB)

The USB is a full-speed/low-speed USB 2.0 compliant host/device controller. The USB can be used in device and host-only configurations, while a clock recovery mechanism allows crystal-less operation in device mode. The USB block supports both full speed (12 MBit/s) and low speed (1.5 MBit/s) operation. When operating as a device, a special Low Energy Mode ensures the current consumption is optimized, enabling USB communications on a strict power budget. The USB device includes an internal dedicated Descriptor-Based Scatter/Gather DMA and supports up to 6 OUT endpoints and 6 IN endpoints, in addition to endpoint 0. The on-chip PHY includes internal pull-up and pull-down resistors, as well as voltage comparators for monitoring the VBUS voltage and A/B device identification using the ID line.

3.6.9 Ethernet (ETH)

The Ethernet peripheral is compliant with IEEE 802.3-2002 for Ethernet MAC. It supports 802.1AS and IEEE 1588 precision clock synchronization protocol, as well as 802.3az Energy Efficient Ethernet. The ETH supports a wide variety of frame formats and standard operating modes such as MII/RMII. Direct Memory Access (DMA) support makes it possible to transmit and receive large frames at high data rates with minimal CPU overhead. The Ethernet peripheral supports 10 Mbps and 100 Mbps operation, and includes a total of 8 kB of dedicated dual-port RAM FIFO (4 kB for TX and 4 kB for RX).

3.6.10 Controller Area Network (CAN)

The CAN peripheral provides support for communication at up to 1 Mbps over CAN protocol version 2.0 part A and B. It includes 32 message objects with independent identifier masks and retains message RAM in EM2. Automatic retransmittion may be disabled in order to support Time Triggered CAN applications.

3.6.11 Peripheral Reflex System (PRS)

The Peripheral Reflex System provides a communication network between different peripheral modules without software involvement. Peripheral modules producing Reflex signals are called producers. The PRS routes Reflex signals from producers to consumer peripherals which in turn perform actions in response. Edge triggers and other functionality such as simple logic operations (AND, OR, NOT) can be applied by the PRS to the signals. The PRS allows peripheral to act autonomously without waking the MCU core, saving power.

3.6.12 Low Energy Sensor Interface (LESENSE)

The Low Energy Sensor Interface LESENSE™ is a highly configurable sensor interface with support for up to 16 individually configurable sensors. By controlling the analog comparators, ADC, and DAC, LESENSE is capable of supporting a wide range of sensors and measurement schemes, and can for instance measure LC sensors, resistive sensors and capacitive sensors. LESENSE also includes a programmable finite state machine which enables simple processing of measurement results without CPU intervention. LESENSE is available in energy mode EM2, in addition to EM0 and EM1, making it ideal for sensor monitoring in applications with a strict energy budget.

4.1.8 Wake Up Times

Table 4.10. Wake Up Times

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Wake up time from EM1	t_{EM1_WU}		—	3	—	AHB Clocks
Wake up from EM2	t_{EM2_WU}	Code execution from flash	—	11.8	—	µs
		Code execution from RAM	—	4.1	—	µs
Wake up from EM3	t_{EM3_WU}	Code execution from flash	—	11.8	—	µs
		Code execution from RAM	—	4.1	—	µs
Wake up from EM4H[1]	t_{EM4H_WU}	Executing from flash	—	94	—	µs
Wake up from EM4S[1]	t_{EM4S_WU}	Executing from flash	—	294	—	µs
Time from release of reset source to first instruction execution	t_{RESET}	Soft Pin Reset released	—	55	—	µs
		Any other reset released	—	359	—	µs
Power mode scaling time	t_{SCALE}	VSCALE0 to VSCALE2, HFCLK = 19 MHz[4] [2]	—	31.8	—	µs
		VSCALE2 to VSCALE0, HFCLK = 19 MHz[3]	—	4.3	—	µs

Note:

1. Time from wake up request until first instruction is executed. Wakeup results in device reset.
2. VSCALE0 to VSCALE2 voltage change transitions occur at a rate of 10 mV/µs for approximately 20 µs. During this transition, peak currents will be dependent on the value of the DECOUPLE output capacitor, from 35 mA (with a 1 µF capacitor) to 70 mA (with a 2.7 µF capacitor).
3. Scaling down from VSCALE2 to VSCALE0 requires approximately 2.8 µs + 29 HFCLKs.
4. Scaling up from VSCALE0 to VSCALE2 requires approximately 30.3 µs + 28 HFCLKs.

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
ADC clock frequency	f_{ADCCLK}		—	—	16	MHz
Throughput rate	$f_{ADCRATE}$		—	—	1	Msps
Conversion time[1]	$t_{ADCCONV}$	6 bit	—	7	—	cycles
		8 bit	—	9	—	cycles
		12 bit	—	13	—	cycles
Startup time of reference generator and ADC core	$t_{ADCSTART}$	WARMUPMODE[4] = NORMAL	—	—	5	µs
		WARMUPMODE[4] = KEEPIN-STANDBY	—	—	2	µs
		WARMUPMODE[4] = KEEPINSLO-WACC	—	—	1	µs
SNDR at 1Msps and f_{IN} = 10kHz	$SNDR_{ADC}$	Internal reference[7], differential measurement	TBD	67	—	dB
		External reference[6], differential measurement	—	68	—	dB
Spurious-free dynamic range (SFDR)	$SFDR_{ADC}$	1 MSamples/s, 10 kHz full-scale sine wave	—	75	—	dB
Differential non-linearity (DNL)	DNL_{ADC}	12 bit resolution, No missing co-des	TBD	—	TBD	LSB
Integral non-linearity (INL), End point method	INL_{ADC}	12 bit resolution	TBD	—	TBD	LSB
Offset error	$V_{ADCOFFSETERR}$		TBD	0	TBD	LSB
Gain error in ADC	$V_{ADCGAIN}$	Using internal reference	—	-0.2	TBD	%
		Using external reference	—	-1	—	%
Temperature sensor slope	V_{TS_SLOPE}		—	-1.84	—	mV/°C

Note:

1. Derived from ADCCLK.
2. PSRR is referenced to AVDD when ANASW=0 and to DVDD when ANASW=1 in EMU_PWRCTRL.
3. In ADCn_BIASPROG register.
4. In ADCn_CNTL register.
5. The absolute voltage allowed at any ADC input is dictated by the power rail supplied to on-chip circuitry, and may be lower than the effective full scale voltage. All ADC inputs are limited to the ADC supply (AVDD or DVDD depending on EMU_PWRCTRL_ANASW). Any ADC input routed through the APORT will further be limited by the IOVDD supply to the pin.
6. External reference is 1.25 V applied externally to ADCnEXTREFP, with the selection CONF in the SINGLECTRL_REF or SCANCTRL_REF register field and VREFP in the SINGLECTRLX_VREFSEL or SCANCTRLX_VREFSEL field. The differential input range with this configuration is ± 1.25 V.
7. Internal reference option used corresponds to selection 2V5 in the SINGLECTRL_REF or SCANCTRL_REF register field. The differential input range with this configuration is ± 1.25 V. Typical value is characterized using full-scale sine wave input. Minimum value is production-tested using sine wave input at 1.5 dB lower than full scale.

4.1.17 Current Digital to Analog Converter (IDAC)

Table 4.25. Current Digital to Analog Converter (IDAC)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Number of ranges	N_{IDAC_RANGES}		—	4	—	ranges
Output current	I_{IDAC_OUT}	RANGSEL[1] = RANGE0	0.05	—	1.6	µA
		RANGSEL[1] = RANGE1	1.6	—	4.7	µA
		RANGSEL[1] = RANGE2	0.5	—	16	µA
		RANGSEL[1] = RANGE3	2	—	64	µA
Linear steps within each range	N_{IDAC_STEPS}		—	32	—	steps
Step size	SS_{IDAC}	RANGSEL[1] = RANGE0	—	50	—	nA
		RANGSEL[1] = RANGE1	—	100	—	nA
		RANGSEL[1] = RANGE2	—	500	—	nA
		RANGSEL[1] = RANGE3	—	2	—	µA
Total accuracy, STEPSEL[1] = 0x10	ACC_{IDAC}	EM0 or EM1, AVDD=3.3 V, T = 25 °C	TBD	—	TBD	%
		EM0 or EM1, Across operating temperature range	TBD	—	TBD	%
		EM2 or EM3, Source mode, RANGSEL[1] = RANGE0, AVDD=3.3 V, T = 25 °C	—	-2.7	—	%
		EM2 or EM3, Source mode, RANGSEL[1] = RANGE1, AVDD=3.3 V, T = 25 °C	—	-2.5	—	%
		EM2 or EM3, Source mode, RANGSEL[1] = RANGE2, AVDD=3.3 V, T = 25 °C	—	-1.5	—	%
		EM2 or EM3, Source mode, RANGSEL[1] = RANGE3, AVDD=3.3 V, T = 25 °C	—	-1.0	—	%
		EM2 or EM3, Sink mode, RANGSEL[1] = RANGE0, AVDD=3.3 V, T = 25 °C	—	-1.1	—	%
		EM2 or EM3, Sink mode, RANGSEL[1] = RANGE1, AVDD=3.3 V, T = 25 °C	—	-1.1	—	%
		EM2 or EM3, Sink mode, RANGSEL[1] = RANGE2, AVDD=3.3 V, T = 25 °C	—	-0.9	—	%
		EM2 or EM3, Sink mode, RANGSEL[1] = RANGE3, AVDD=3.3 V, T = 25 °C	—	-0.9	—	%

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Start up time	t_{IDAC_SU}	Output within 1% of steady state value	—	5	—	µs
Settling time, (output settled within 1% of steady state value),	t_{IDAC_SETTLE}	Range setting is changed	—	5	—	µs
		Step value is changed	—	1	—	µs
Current consumption[2]	I_{IDAC}	EM0 or EM1 Source mode, excluding output current, Across operating temperature range	—	11	TBD	µA
		EM0 or EM1 Sink mode, excluding output current, Across operating temperature range	—	13	TBD	µA
		EM2 or EM3 Source mode, excluding output current, T = 25 °C	—	0.05	—	µA
		EM2 or EM3 Sink mode, excluding output current, T = 25 °C	—	0.07	—	µA
		EM2 or EM3 Source mode, excluding output current, T ≥ 85 °C	—	11	—	µA
		EM2 or EM3 Sink mode, excluding output current, T ≥ 85 °C	—	13	—	µA
Output voltage compliance in source mode, source current change relative to current sourced at 0 V	I_{COMP_SRC}	RANGESEL1=0, output voltage = min(V_{IOVDD}, V_{AVDD}[2]-100 mv)	—	0.11	—	%
		RANGESEL1=1, output voltage = min(V_{IOVDD}, V_{AVDD}[2]-100 mV)	—	0.06	—	%
		RANGESEL1=2, output voltage = min(V_{IOVDD}, V_{AVDD}[2]-150 mV)	—	0.04	—	%
		RANGESEL1=3, output voltage = min(V_{IOVDD}, V_{AVDD}[2]-250 mV)	—	0.03	—	%
Output voltage compliance in sink mode, sink current change relative to current sunk at IOVDD	I_{COMP_SINK}	RANGESEL1=0, output voltage = 100 mV	—	0.29	—	%
		RANGESEL1=1, output voltage = 100 mV	—	0.27	—	%
		RANGESEL1=2, output voltage = 150 mV	—	0.12	—	%
		RANGESEL1=3, output voltage = 250 mV	—	0.03	—	%

Note:

1. In IDAC_CURPROG register.
2. The IDAC is supplied by either AVDD, DVDD, or IOVDD based on the setting of ANASW in the EMU_PWRCTRL register and PWRSEL in the IDAC_CTRL register. Setting PWRSEL to 1 selects IOVDD. With PWRSEL cleared to 0, ANASW selects between AVDD (0) and DVDD (1).

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Supply current, continuous conversions, WARMUP-MODE=KEEPCSENWARM	I_{CSEN_ACTIVE}	SAR or Delta Modulation conversions of 33 pF capacitor, CS0CG=0 (Gain = 10x), always on	—	90.5	—	µA
HFPERCLK supply current	$I_{CSEN\_HFPERCLK}$	Current contribution from HFPERCLK when clock to CSEN block is enabled.	—	2.25	—	µA/MHz

Note:

1. Current is specified with a total external capacitance of 33 pF per channel. Average current is dependent on how long the module is actively sampling channels within the scan period, and scales with the number of samples acquired. Supply current for a specific application can be estimated by multiplying the current per sample by the total number of samples per period (total_current = single_sample_current * (number_of_channels * accumulation)).

EBI Read Enable Output Timing

Timing applies to both EBI_REn and EBI_NANDREn for all addressing modes and both polarities. Output timing for EBI_AD applies only to multiplexed addressing modes D8A24ALE and D16A16ALE. All numbers are based on route locations 0,1,2 only (with all EBI alternate functions using the same location at the same time). Timing is specified at 10% and 90% of IOVDD, 25 pF external loading, and slew rate for all GPIO set to 6.

Table 4.38. EBI Read Enable Output Timing

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Output hold time, from trailing EBI_REn / EBI_NANDREn edge to EBI_AD, EBI_A, EBI_CSn, EBI_BLn invalid	t_{OH_REn}	IOVDD ≥ 1.62 V	-23 + (RDHOLD * $t_{HFCORECLK}$)	—	—	ns
		IOVDD ≥ 3.0 V	-13 + (RDHOLD * $t_{HFCORECLK}$)	—	—	ns
Output setup time, from EBI_AD, EBI_A, EBI_CSn, EBI_BLn valid to leading EBI_REn / EBI_NANDREn edge [1]	t_{OSU_REn}	IOVDD ≥ 1.62 V	-12 + (RDSETUP * $t_{HFCORECLK}$)	—	—	ns
		IOVDD ≥ 3.0 V	-11 + (RDSETUP * $t_{HFCORECLK}$)	—	—	ns
EBI_REn pulse width[1] [2]	t_{WIDTH_REn}	IOVDD ≥ 1.62 V	-6 + (MAX(1, RDSTRB) * $t_{HFCORECLK}$)	—	—	ns
		IOVDD ≥ 3.0 V	-4 + (MAX(1, RDSTRB) * $t_{HFCORECLK}$)	—	—	ns

Note:

1. The figure shows the timing for the case that the half strobe length functionality is not used, i.e. HALFRE=0. The leading edge of EBI_REn can be moved to the right by setting HALFRE=1. This decreases the length of t_{WIDTH_REn} and increases the length of t_{OSU_REn} by 1/2 * $t_{HFCLKNODIV}$.
2. When page mode is used, RDSTRB is replaced by RDPA for page hits.

EBI Read Enable Timing Requirements

Timing applies to both EBI_REn and EBI_NANDREn for all addressing modes and both polarities. All numbers are based on route locations 0,1,2 only (with all EBI alternate functions using the same location at the same time). Timing is specified at 10% and 90% of IOVDD, 25 pF external loading, and slew rate for all GPIO set to 6.

Table 4.40. EBI Read Enable Timing Requirements

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Setup time, from EBI_AD valid to trailing EBI_REn edge	t_{SU_REn}	IOVDD ≥ 1.62 V	55	—	—	ns
		IOVDD ≥ 3.0 V	36	—	—	ns
Hold time, from trailing EBI_REn edge to EBI_AD invalid	t_{H_REn}	IOVDD ≥ 1.62 V	-9	—	—	ns

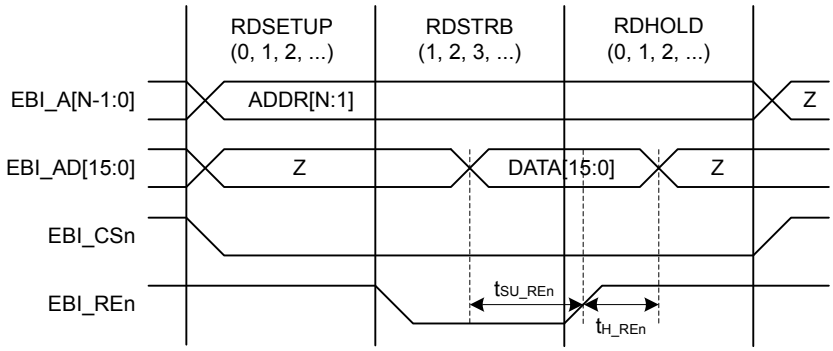

Figure 4.7. EBI Read Enable Timing Requirements

SDIO MMC DDR Mode Timing at 3.0 V

Timing is specified for route location 0 at 3.0 V IOVDD with voltage scaling disabled. Slew rate for SD_CLK set to 7, all other GPIO set to 6, DRIVESTRENGTH = STRONG for all pins. SDIO_CTRL_TXDLYMUXSEL = 1. Loading between 5 and 10 pF on all pins or between 10 and 25 pF on all pins.

Table 4.53. SDIO MMC DDR Mode Timing (Location 0, 3V I/O)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Clock frequency during data transfer	F_{SD_CLK}	Using HFRCO, AUXHFRCO, or USHFRCO	—	—	20	MHz
		Using HFXO	—	—	TBD	MHz
Clock low time	t_{WL}	Using HFRCO, AUXHFRCO, or USHFRCO	22.6	—	—	ns
		Using HFXO	TBD	—	—	ns
Clock high time	t_{WH}	Using HFRCO, AUXHFRCO, or USHFRCO	22.6	—	—	ns
		Using HFXO	TBD	—	—	ns
Clock rise time	t_R		1.13	2.37	—	ns
Clock fall time	t_F		1.01	2.02	—	ns
Input setup time, CMD valid to SD_CLK	t_{ISU}		5.3	—	—	ns
Input hold time, SD_CLK to CMD change	t_{IH}		2.5	—	—	ns
Output delay time, SD_CLK to CMD valid	t_{ODLY}		0	—	16	ns
Output hold time, SD_CLK to CMD change	t_{OH}		3	—	—	ns
Input setup time, DAT[0:7] valid to SD_CLK	t_{ISU2X}		5.3	—	—	ns
Input hold time, SD_CLK to DAT[0:7] change	t_{IH2X}		2.5	—	—	ns
Output delay time, SD_CLK to DAT[0:7] valid	t_{ODLY2X}		0	—	16	ns
Output hold time, SD_CLK to DAT[0:7] change	t_{OH2X}		3	—	—	ns

4.1.28.2 QSPI DDR Mode

QSPI DDR Mode Timing (Location 0)

Timing is specified with voltage scaling disabled, PHY-mode, route location 0 only, TX DLL = 35, RX DLL = 70, 20-25 pF loading per GPIO, and slew rate for all GPIO set to 6, DRIVESTRENGTH = STRONG.

Table 4.56. QSPI DDR Mode Timing (Location 0)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Half SCLK period	T/2	HFXO	$(1/F_{SCLK})$ * 0.4 - 0.4	—	—	ns
		HFRCO, AUXHFRCO, USHFRCO	$(1/F_{SCLK})$ * 0.44	—	—	ns
Output valid	t_{OV}		—	—	T/2 - 5.0	ns
Output hold	t_{OH}		T/2 - 39.4	—	—	ns
Input setup	t_{SU}		33.1	—	—	ns
Input hold	t_H		-0.9	—	—	ns

Alternate	LOCATION		
Functionality	0 - 3	4 - 7	Description
LCD_BEXT	0: PA14		LCD external supply bypass in step down or charge pump mode. If using the LCD in step-down or charge pump mode, a 1 uF (minimum) capacitor between this pin and VSS is required. To reduce supply ripple, a larger capcitor of approximately 1000 times the total LCD segment capacitance may be used. If using the LCD with the internal supply source, this pin may be left unconnected or used as a GPIO.
LCD_COM0	0: PE4		LCD driver common line number 0.
LCD_COM1	0: PE5		LCD driver common line number 1.
LCD_COM2	0: PE6		LCD driver common line number 2.
LCD_COM3	0: PE7		LCD driver common line number 3.
LCD_SEG0	0: PF2		LCD segment line 0.
LCD_SEG1	0: PF3		LCD segment line 1.
LCD_SEG2	0: PF4		LCD segment line 2.
LCD_SEG3	0: PF5		LCD segment line 3.
LCD_SEG4	0: PE8		LCD segment line 4.
LCD_SEG5	0: PE9		LCD segment line 5.
LCD_SEG6	0: PE10		LCD segment line 6.

Alternate	LOCATION		
Functionality	0 - 3	4 - 7	Description
LCD_SEG7	0: PE11		LCD segment line 7.
LCD_SEG8	0: PE12		LCD segment line 8.
LCD_SEG9	0: PE13		LCD segment line 9.
LCD_SEG10	0: PE14		LCD segment line 10.
LCD_SEG11	0: PE15		LCD segment line 11.
LCD_SEG12	0: PA15		LCD segment line 12.
LCD_SEG13	0: PA0		LCD segment line 13.
LCD_SEG14	0: PA1		LCD segment line 14.
LCD_SEG15	0: PA2		LCD segment line 15.
LCD_SEG16	0: PA3		LCD segment line 16.
LCD_SEG17	0: PA4		LCD segment line 17.
LCD_SEG18	0: PA5		LCD segment line 18.
LCD_SEG19	0: PA6		LCD segment line 19.

Table 5.23. ACMP0 Bus and Pin Mapping

Port	Bus	CH31	CH30	CH29	CH28	CH27	CH26	CH25	CH24	CH23	CH22	CH21	CH20	CH19	CH18	CH17	CH16	CH15	CH14	CH13	CH12	CH11	CH10	CH9	CH8	CH7	CH6	CH5	CH4	CH3	CH2	CH1	CH0
APORT0X	BUSACMP0X																									PC7	PC6	PC5	PC4	PC3	PC2	PC1	PC0
APORT0Y	BUSACMP0Y																									PC7	PC6	PC5	PC4	PC3	PC2	PC1	PC0
APORT1X	BUSAX		PB14		PB12		PB10				PB6		PB4		PB2		PB0		PA14		PA12		PA10		PA8		PA6		PA4		PA2		PA0
APORT1Y	BUSAY	PB15		PB13		PB11		PB9				PB5		PB3		PB1		PA15		PA13		PA11		PA9		PA7		PA5		PA3		PA1	
APORT2X	BUSBX	PB15		PB13		PB11		PB9				PB5		PB3		PB1		PA15		PA13		PA11		PA9		PA7		PA5		PA3		PA1	
APORT2Y	BUSBY		PB14		PB12		PB10				PB6		PB4		PB2		PB0		PA14		PA12		PA10		PA8		PA6		PA4		PA2		PA0
APORT3X	BUSCX		PF14		PF12		PF10		PF8		PF6		PF4		PF2		PF0		PE14		PE12		PE10		PE8		PE6		PE4				PE0
APORT3Y	BUSCY	PF15		PF13		PF11		PF9		PF7		PF5		PF3		PF1		PE15		PE13		PE11		PE9		PE7		PE5				PE1	
APORT4X	BUSDX	PF15		PF13		PF11		PF9		PF7		PF5		PF3		PF1		PE15		PE13		PE11		PE9		PE7		PE5				PE1	
APORT4Y	BUSDY		PF14		PF12		PF10		PF8		PF6		PF4		PF2		PF0		PE14		PE12		PE10		PE8		PE6		PE4				PE0

Table 5.27. ADC0 Bus and Pin Mapping

Port	Bus	CH31	CH30	CH29	CH28	CH27	CH26	CH25	CH24	CH23	CH22	CH21	CH20	CH19	CH18	CH17	CH16	CH15	CH14	CH13	CH12	CH11	CH10	CH9	CH8	CH7	CH6	CH5	CH4	CH3	CH2	CH1	CH0
APORT0X	BUSADC0X																									PD7	PD6	PD5	PD4	PD3	PD2	PD1	PD0
APORT0Y	BUSADC0Y																									PD7	PD6	PD5	PD4	PD3	PD2	PD1	PD0
APORT1X	BUSAX		PB14		PB12		PB10				PB6		PB4		PB2		PB0		PA14		PA12		PA10		PA8		PA6		PA4		PA2		PA0
APORT1Y	BUSAY	PB15		PB13		PB11		PB9				PB5		PB3		PB1		PA15		PA13		PA11		PA9		PA7		PA5		PA3		PA1	
APORT2X	BUSBX	PB15		PB13		PB11		PB9				PB5		PB3		PB1		PA15		PA13		PA11		PA9		PA7		PA5		PA3		PA1	
APORT2Y	BUSBY		PB14		PB12		PB10				PB6		PB4		PB2		PB0		PA14		PA12		PA10		PA8		PA6		PA4		PA2		PA0
APORT3X	BUSCX		PF14		PF12		PF10		PF8		PF6		PF4		PF2		PF0		PE14		PE12		PE10		PE8		PE6		PE4				PE0
APORT3Y	BUSCY	PF15		PF13		PF11		PF9		PF7		PF5		PF3		PF1		PE15		PE13		PE11		PE9		PE7		PE5				PE1	
APORT4X	BUSDX	PF15		PF13		PF11		PF9		PF7		PF5		PF3		PF1		PE15		PE13		PE11		PE9		PE7		PE5				PE1	
APORT4Y	BUSDY		PF14		PF12		PF10		PF8		PF6		PF4		PF2		PF0		PE14		PE12		PE10		PE8		PE6		PE4				PE0

Table 5.28. ADC1 Bus and Pin Mapping

Port	Bus	CH31	CH30	CH29	CH28	CH27	CH26	CH25	CH24	CH23	CH22	CH21	CH20	CH19	CH18	CH17	CH16	CH15	CH14	CH13	CH12	CH11	CH10	CH9	CH8	CH7	CH6	CH5	CH4	CH3	CH2	CH1	CH0
APORT0X	BUSADC1X																									PH7	PH6	PH5	PH4	PH3	PH2	PH1	PH0
APORT0Y	BUSADC1Y																									PH7	PH6	PH5	PH4	PH3	PH2	PH1	PH0
APORT1X	BUSAX		PB14		PB12		PB10				PB6		PB4		PB2		PB0		PA14		PA12		PA10		PA8		PA6		PA4		PA2		PA0
APORT1Y	BUSAY	PB15		PB13		PB11		PB9				PB5		PB3		PB1		PA15		PA13		PA11		PA9		PA7		PA5		PA3		PA1	
APORT2X	BUSBX	PB15		PB13		PB11		PB9				PB5		PB3		PB1		PA15		PA13		PA11		PA9		PA7		PA5		PA3		PA1	
APORT2Y	BUSBY		PB14		PB12		PB10				PB6		PB4		PB2		PB0		PA14		PA12		PA10		PA8		PA6		PA4		PA2		PA0
APORT3X	BUSCX		PF14		PF12		PF10		PF8		PF6		PF4		PF2		PF0		PE14		PE12		PE10		PE8		PE6		PE4				PE0
APORT3Y	BUSCY	PF15		PF13		PF11		PF9		PF7		PF5		PF3		PF1		PE15		PE13		PE11		PE9		PE7		PE5				PE1	
APORT4X	BUSDX	PF15		PF13		PF11		PF9		PF7		PF5		PF3		PF1		PE15		PE13		PE11		PE9		PE7		PE5				PE1	
APORT4Y	BUSDY		PF14		PF12		PF10		PF8		PF6		PF4		PF2		PF0		PE14		PE12		PE10		PE8		PE6		PE4				PE0

Table 5.31. VDAC0 / OPA Bus and Pin Mapping

Port	Bus	CH31	CH30	CH29	CH28	CH27	CH26	CH25	CH24	CH23	CH22	CH21	CH20	CH19	CH18	CH17	CH16	CH15	CH14	CH13	CH12	CH11	CH10	CH9	CH8	CH7	CH6	CH5	CH4	CH3	CH2	CH1	CH0
OPA0_N																																	
APORT1Y	BUSAY	PB15		PB13		PB11		PB9				PB5		PB3		PB1		PA15		PA13		PA11		PA9		PA7		PA5		PA3		PA1	
APORT2Y	BUSBY		PB14		PB12		PB10				PB6		PB4		PB2		PB0		PA14		PA12		PA10		PA8		PA6		PA4		PA2		PA0
APORT3Y	BUSCY	PF15		PF13		PF11		PF9		PF7		PF5		PF3		PF1		PE15		PE13		PE11		PE9		PE7		PE5				PE1	
APORT4Y	BUSDY		PF14		PF12		PF10		PF8		PF6		PF4		PF2		PF0		PE14		PE12		PE10		PE8		PE6		PE4				PE0
OPA0_P																																	
APORT1X	BUSAX		PB14		PB12		PB10				PB6		PB4		PB2		PB0		PA14		PA12		PA10		PA8		PA6		PA4		PA2		PA0
APORT2X	BUSBX	PB15		PB13		PB11		PB9				PB5		PB3		PB1		PA15		PA13		PA11		PA9		PA7		PA5		PA3		PA1	
APORT3X	BUSCX		PF14		PF12		PF10		PF8		PF6		PF4		PF2		PF0		PE14		PE12		PE10		PE8		PE6		PE4				PE0
APORT4X	BUSDX	PF15		PF13		PF11		PF9		PF7		PF5		PF3		PF1		PE15		PE13		PE11		PE9		PE7		PE5				PE1	

6.2 BGA192 PCB Land Pattern

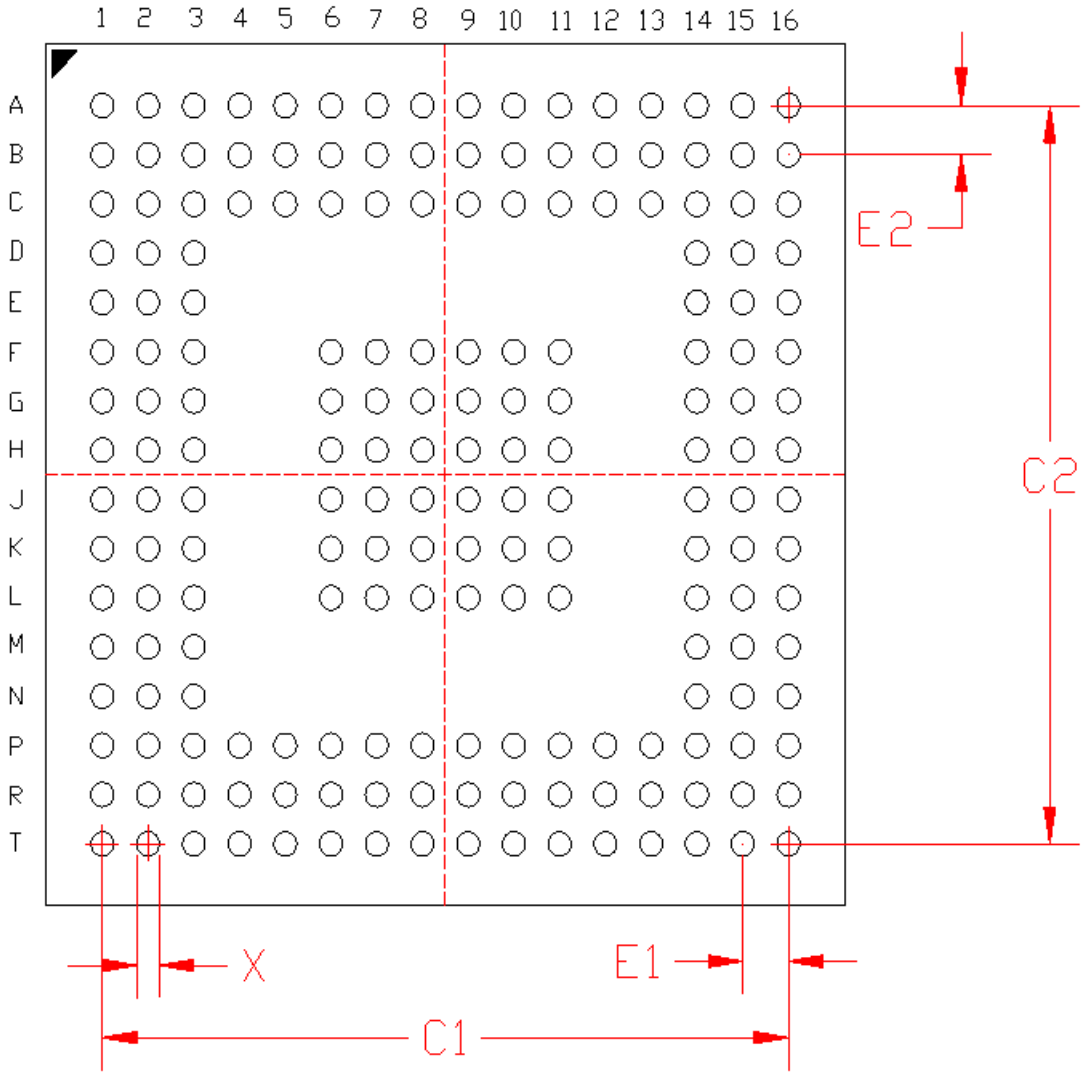

Figure 6.2. BGA192 PCB Land Pattern Drawing

Table 7.1. BGA152 Package Dimensions

Dimension	Min	Typ	Max
A	0.78	0.84	0.90
A1	0.13	0.18	0.23
A3	0.16	0.20	0.24
A2		0.45 REF	
D		8.00 BSC	
e		0.50 BSC	
E		8.00 BSC	
D1		6.50 BSC	
E1		6.50 BSC	
b	0.20	0.25	0.30
aaa		0.10	
bbb		0.10	
ddd		0.08	
eee		0.15	
fff		0.05	

Note:
1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

11. TQFP64 Package Specifications

11.1 TQFP64 Package Dimensions

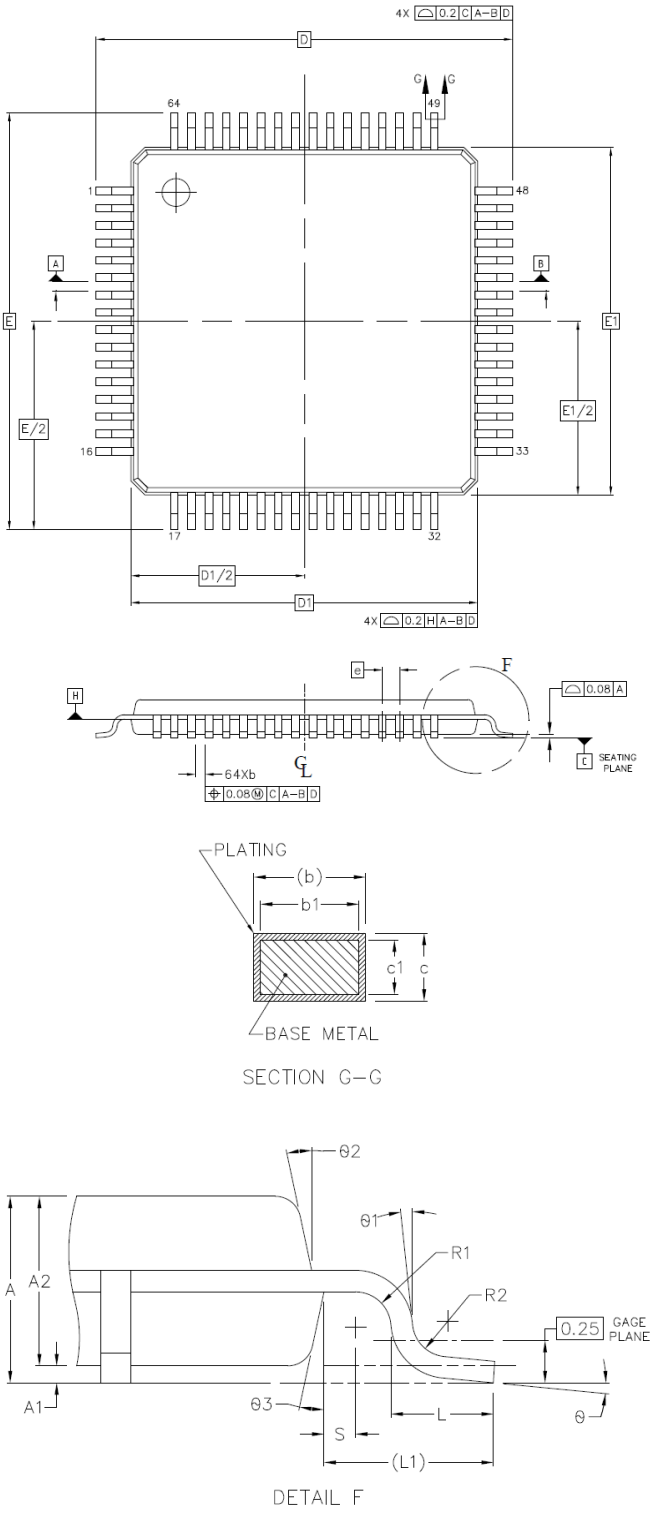

Figure 11.1. TQFP64 Package Drawing